Search Notes



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Applicant(s)/Patent Under Reexamination

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Examiner

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709	220 (updated 1/18/2007)	8/14/2007	MEK

SEARCH NOTES

Search Notes	Date	Examiner
EAST Search	8/14/2007	MEK
Consulted Examiner Dustin Nguyen	8/13/2007	MEK
Google Search	8/14/2007	MEK
709/220-222 keyword limited	8/14/2007	MEK
EAST Search	1/18/2007	MEK

INTERFERENCE SEARCH

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